Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/680,171	TENG, TOM	
Examiner	**Art Unit**	
David E. Martinez	2181	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East see attached	12/28/2006	DM
Databases: US Patents, US PGPUBS, USOCR, EPO, JPO, Derwent, IBM_TDB.	12/28/2006	DM
710/52-61.ccls. 709/231-234.ccls. with keywords and text search	12/28/2006	DM